EMC COMPO 2024 - Tally

Question #1
Please, select the paper presented by a non-student participant that you believe deserves the Best Paper Award. Invited and tutorial talks are not eligible for this award.

#10 - A. Boyer, F. Caignet - Analysis of Operational Amplifier Susceptibility to Multifrequency Disturbance	5
#9 - A. Rosa, A. Richelli, L. Colalongo - EMI Immunity of the Nauta Inverter-Based Amplifier	1
#11 - K. Abouda, M. Bacchi - System-On-Chip Preventing Discharge of Bootstrap Capacitor of High-Side Drivers	4
#33 - T. Nomura, M. Hasegawa, K. Oyama, Y. Kondo, K. Ichikawa - Evaluation of Ground Terminal Against Noise by Direct Power Injection Method	0
#35 - H. H. Park, J. Kim, E. Song, H. Kim, S. Cho - Influence of Sensing Resistor on IC-Level Noise Measurement of DC-DC Converters by 1 Ω Method	1
#27 - J. Ruau, B. Vrignon, C. Menard, L. Liu, M. Baudry - Near Field Scan Investigation Method to Reduce 4.8GHz Emission on a BLE Application	2
#17 - K. Shimada, M. Okushima - On-Chip ESD Current Sensor for Nanosecond Oscillation Waveform Over Ampere Detecting	5
#12 - H. Sugo, N. Oka, T. Nagai, K. Hattori, T. Matsuzaki - An ICIM-CI Model for Mass Production Development Considering Manufacturing Variations	3
#25 - J. Wu, Y. Lu, Y. Li, H. Zhang, Y. Zhang, X. Zhao, W. Zhu - STT-MRAM Based ESD and EFT Immunity Analysis	0
#41 - M. Singh Choudhary, J. M. Redouté, M. Shojaei Baghini - Comprehensive Study of EMI Effects on Wireline Transceiver Systems: A Review of Silicon-Proven Techniques	9

#67 - T. Wadatsumi, R. Hasegawa, K. Monta, T. Miki, L. Lin, N. Chang, M. Nagata - Modeling and Analysis of On-Chip Voltage Fluctuations Caused by Electromagnetic Fault Injection	1
#55 - M. Hameed, A. Reithofer, G. Fellner, A. Hosseinbeig, D. Pommerenke - Analysis, Testing and Comparison of Different Commercial ESD Detectors	0
#44 - S. Jahn - Functional Failures in a Sensor Application Caused by System-Level ESD	2
#42 - M. Schulz, M. Kopf - Passive DC-Input and DC-Input/AC-Output EMI Filter for DC-AC Inverter	1
#61 - M. Fishta, P. Montorsi, F. Fiori - A Critical Analysis of Amplifier Requirements in Capacitance-Boosting Circuits for EMI Reduction	5
#69 - S. Miropolsky, F. Klotz - Analysis of Partial RF Emission Spectra of IC Functions and Subcircuits on the Example of Power Switch ICs	4
#36 - M. Tranchero, M. Garelli - Measurement of PCB-Related Commutation-Loop Inductance Using a Vector Network Analyzer	0
#46 - A. Schade, F. Klotz, R. Weigel - Automated Method to Synthesize RLCK-Circuits From S-Parameters	5
#48 - A. Schade, F. Klotz, R. Weigel - Loop Inductance Based RLCK Models of PCBs and IC-Packages in Practice	0
#64 - F. De Paulis, F. Squires, Y. Ding, M. Cocchini, M. Doyle, S. Connor, A. Ruehli, C. Hwang, L. Jiang - Suppression of Power Distribution Network PCB-Package Resonance for Low Target Impedance	1
#66 - S. Negri, X. Liu, G. Spadacini, F. Grassi, S. Pignari, A. Sanna, D. Halicki - Investigation on the Effect of Different Form Factors on the Performance of Miniaturized Transformers	1
#15 - N. Seliger, N. Leirich - Reconfigurable Board-To-Board Interconnect Utilizing Bistable Compliant Ribbon Wires	0

#23 - P. K. Gupta, R. Halba - SPICE Based SI-PI Co-Simulation Framework to Optimize Die-Package-PCB to Meet LPDDR5(x) Performance in Automotive and Edge MPU-MCU	0
#51 - D. Fujimoto, T. Sato, Y. Hayashi - Current Consumption Modeling of Logic Cells Based on Measurements for Side-Channel Attack Simulation	0
#19 - S. Y. Yuan, S. H. Chiang, Y. L. Wang, L. Y. Lin, Y. F. Ku - Clock Signal Recovery Algorithm for FPGA-Based Microcontroller Near-Field EMI Measurement and Processing	0

Question #2
Please, select the paper presented by a student participant that you believe deserves the Best Student Paper Award.

#40 - D. Zupan, N. Czepl, B. Deutschmann - Characterisation of an EMI-Improved Integrated Folded Cascode Amplifier Structure Using the EMIRR Measurement Method	6
#26 - T. Billaux, J. Raoult, P. Hoffmann - Analyzing and Modeling of the Susceptibility to Temporary Malfunction in Automatic Gain Control Loops	3
#34 - P. Maurine, J. Raoult, A. Mouette, J. Toulemont - Butterfly Probes: Estimating the Derivative of the Magnetic Flux	4
#28 - A. H. Venkateshaiah, J. F. Dawson, M. Trefzer, S. Bale, A. Marvin, M. Robinson - Design and Application of RFIC Detector: To Measure Coupled Power Into IC Pin via PCB Trace	2
#50 - M. Laidet, A. Boyer, S. Ben Dhia, J. Gazave - Accelerated Characterisation of Operational Amplifiers' Susceptibility Using Multitone Disturbance	3
#47 - T. Monopoli, X. Wu, S. A. Pignari, K. F. J. Wolf, F. Grassi - Inspection Tools for Gaussian Process Regression Modeling of Electromagnetic Fields of Electronic Boards and Chips	1
#39 - M. M. Alam, R. Perdriau, M. Ramdani, M. Koohetsani - A Case Study for the EMC Co-Simulation of Injection Path Model Using WR Method	0

#24 - D. Kreindl, B. Weiss, C. Stockreiter, T. Bauernfeind, M. Kaltenbacher - A Simulation Workflow for Predicting IC Stripline Radiated Emissions of Bond Wire-Based Systems	3
#30 - S. Le Bihan, T. Dubois, J. B. Begueret, A. El Abbazi - Enhancing High-Speed Ethernet Link Design at 25 Gbps in Aerospace Environments Through Optimization Algorithms	8
#21 - R. Dai, Y. Xu, J. Qiu, H. Ma, E. P. Li - High-Fidelity S-Parameter Prediction Using Transfer Learning Based Encoder-Decoder Model	0
#63 - D. Kircher, C. Ionascu, B. Deutschmann - EMI Robust Comparator Design for Protection Features of Smart Power Switches	1
#49 - M. Pfeifer, K. Odreitz, B. Deutschmann - Evaluation of the Electromagnetic Emission of ICs Using Different Spread Spectrum Approaches	2
#14 - N. Czepl, D. Zupan, A. Michalowska-Forsyth, B. Deutschmann - Effects of Ionizing Radiation on the EMI-Induced Offset Voltage of Operational Amplifiers	0
#57 - H. Uehara, K. Watanabe, S. Ashida, Y. Mitsuya, S. Tanaka, M. Nagata - Accuracy of GPS Positioning Measurements in Response to Electromagnetic Noise Characteristics	1
#29 - L. Cesbron Lavau, M. Suhrke, P. Knott - Assessing IEMI Vulnerabilities in MEMS Barometers: A Comparative Approach	0
#16 - A. Duguet, T. Dubois, G. Duchamp, D. Hardy, F. Salvador - Susceptibility of an Analog Temperature Measurement Function: First Step to Optimize the IEMI Waveform	1
#62 - H. Nishiyama, D. Fujimoto, Y. Hayashi - Controlling Faulty Byte Outputs With IEMI Against Cryptographic ICs	2
#60 - A. Barbaro, M. Fishta, E. Raviola, F. Fiori - A Comparison of Spread Spectrum and Sigma Delta Modulations to Mitigate Conducted EMI in GaN-Based DC-DC Converters	10

#37 - C. Liu, F. Blaabjerg, P. Davari - DM EMI Noise Prediction for BCM Based Single-Phase Grid-Connected Inverter	3
#58 - A. Malina Scambor, C. Maier - Investigations on Microstrip and Ground Plane Inductance for Conducted EMI Modelling	0
#65 - K. Abe, D. Fujimoto, Y. Hayashi - Fundamental Study on Detecting Hardware Trojans in Printed Circuit Boards Using Ring Oscillators	0
#20 - C. Ledong, J. Wu, C. Han, H. Liu, X. Wang- Research and Application Progress on Electromagnetic Reliability of Integrated Circuits in the Past Decade	0
#38 - Y. Kaneko, Y. Hayashi, N. Homma - Experimental Evaluation for Detecting Aging Effect on Microcontrollers Based on Side-Channel Analysis	0